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(12) **United States Design Patent**
Ishii

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(54) **OPTICAL MEASURING THEODOLITE USING LIGHT WAVE**

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(**) Term: **15 Years**

(21) Appl. No.: **29/536,904**

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(30) **Foreign Application Priority Data**

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(51) **LOC (10) Cl.** **10-04**

(52) **U.S. Cl.**
USPC **D10/66**

(58) **Field of Classification Search**
USPC D10/66
CPC G01C 1/00; G01C 1/02; G01C 1/04;
G01C 1/06; G01C 1/08; G01C
1/10; G01C 1/12; G01C 1/14

See application file for complete search history.

(56) **References Cited**

U.S. PATENT DOCUMENTS

D723,953 S * 3/2015 Ishii D10/66

* cited by examiner

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(57) **CLAIM**

The ornamental design for an optical measuring theodolite using light wave, as shown and described.

DESCRIPTION

FIG. 1 is a front elevational view of the optical measuring theodolite using light wave;

FIG. 2 is a rear elevational view thereof;

FIG. 3 is a left-side elevational view thereof;

FIG. 4 is a right-side elevational view thereof;

FIG. 5 is a top plan view thereof;

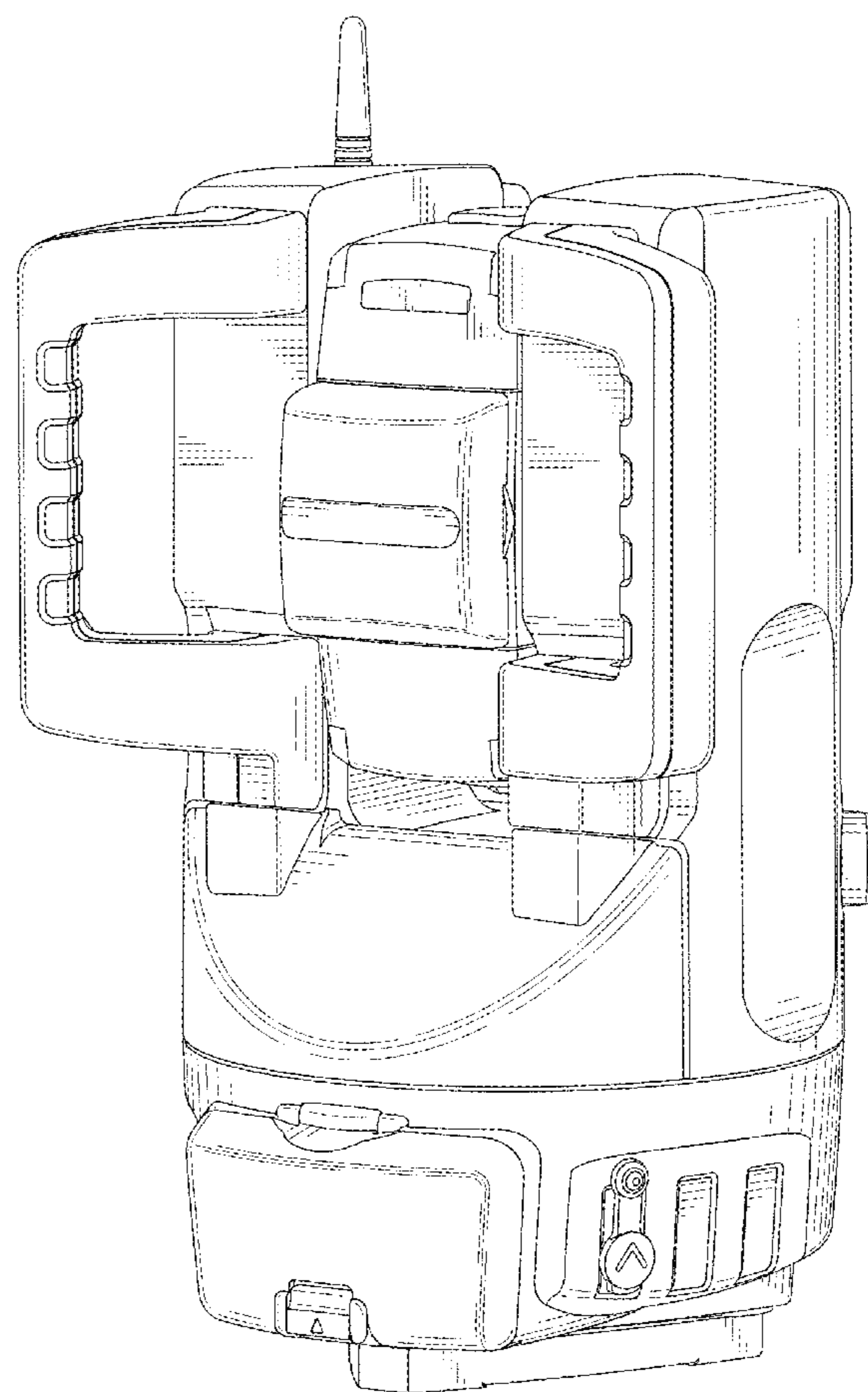
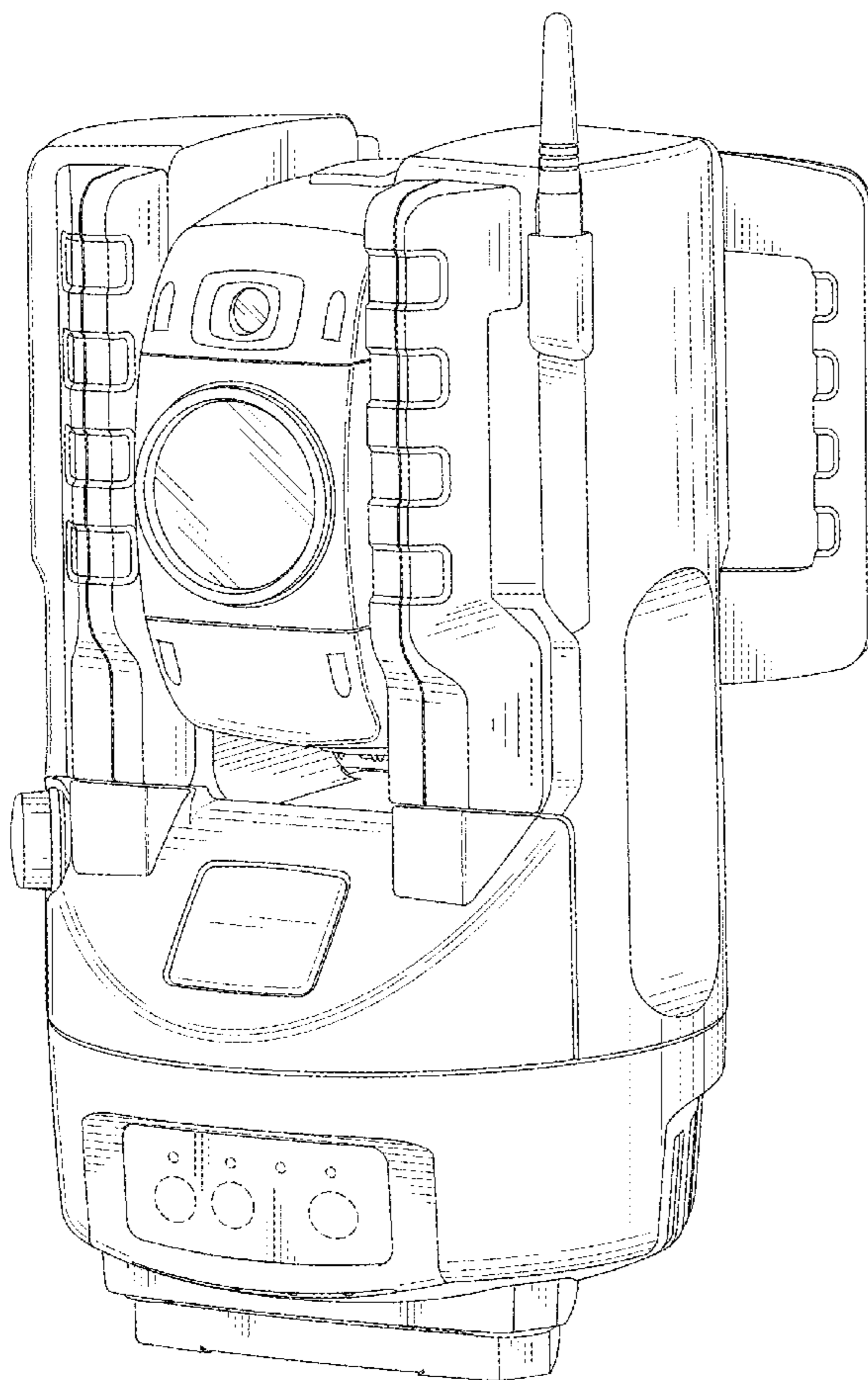
FIG. 6 is a bottom plan view thereof;

FIG. 7 is a front, right-side perspective view thereof; and,

FIG. 8 is a rear, left-side perspective view thereof.

The broken lines depict environmental subject matter only and form no part of the claimed design.

1 Claim, 8 Drawing Sheets



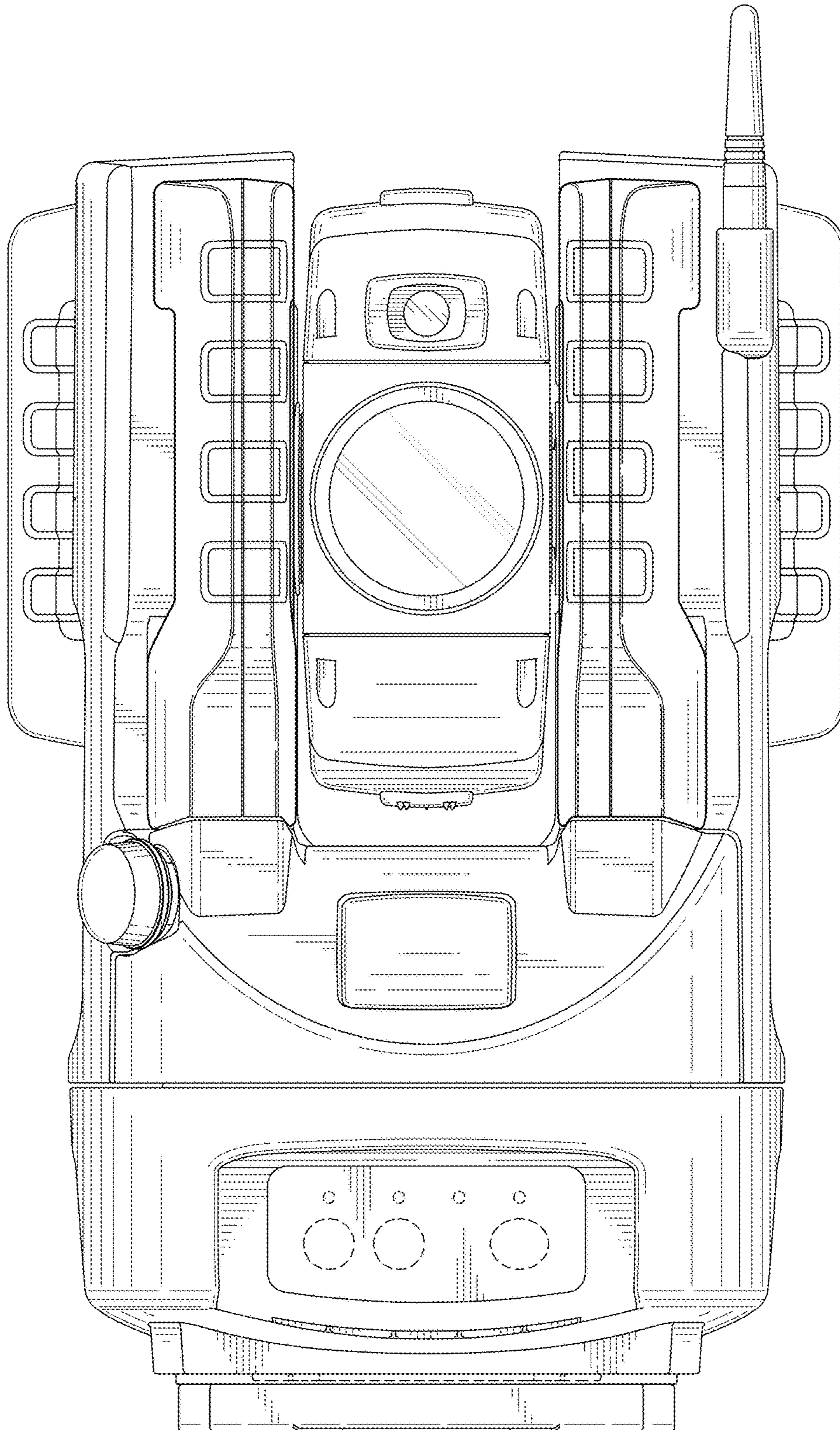


FIG. 1

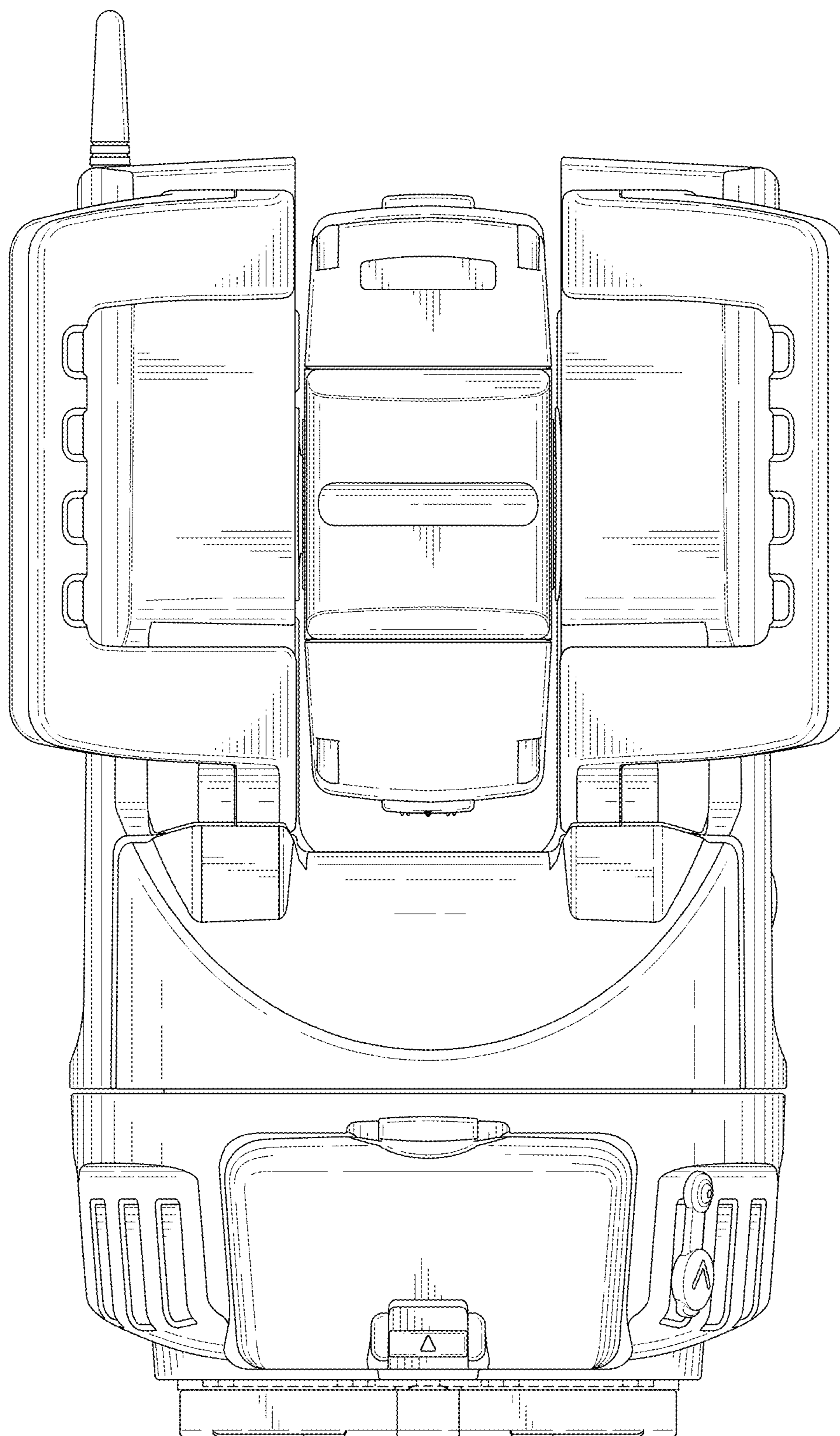


FIG. 2

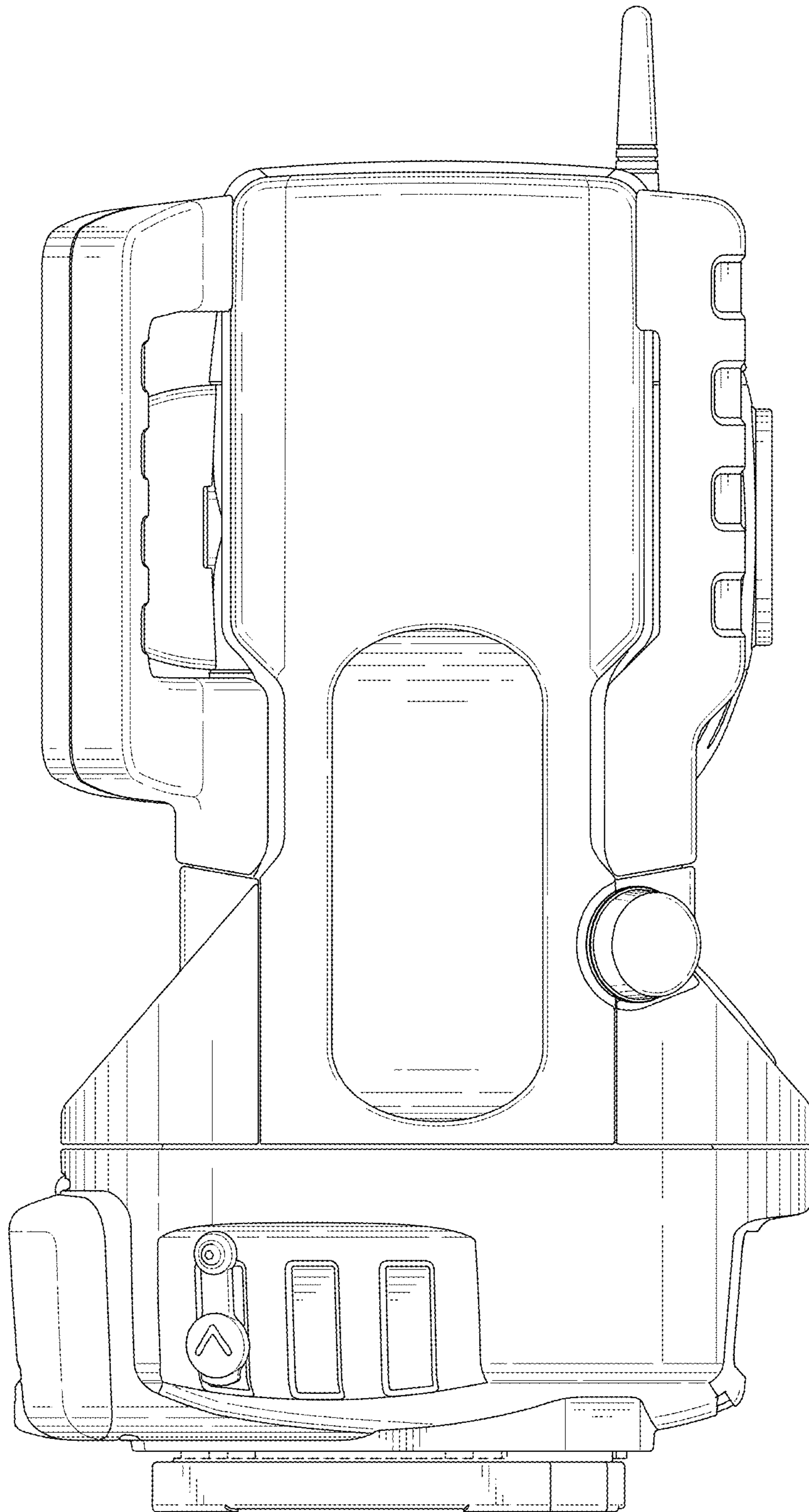


FIG. 3

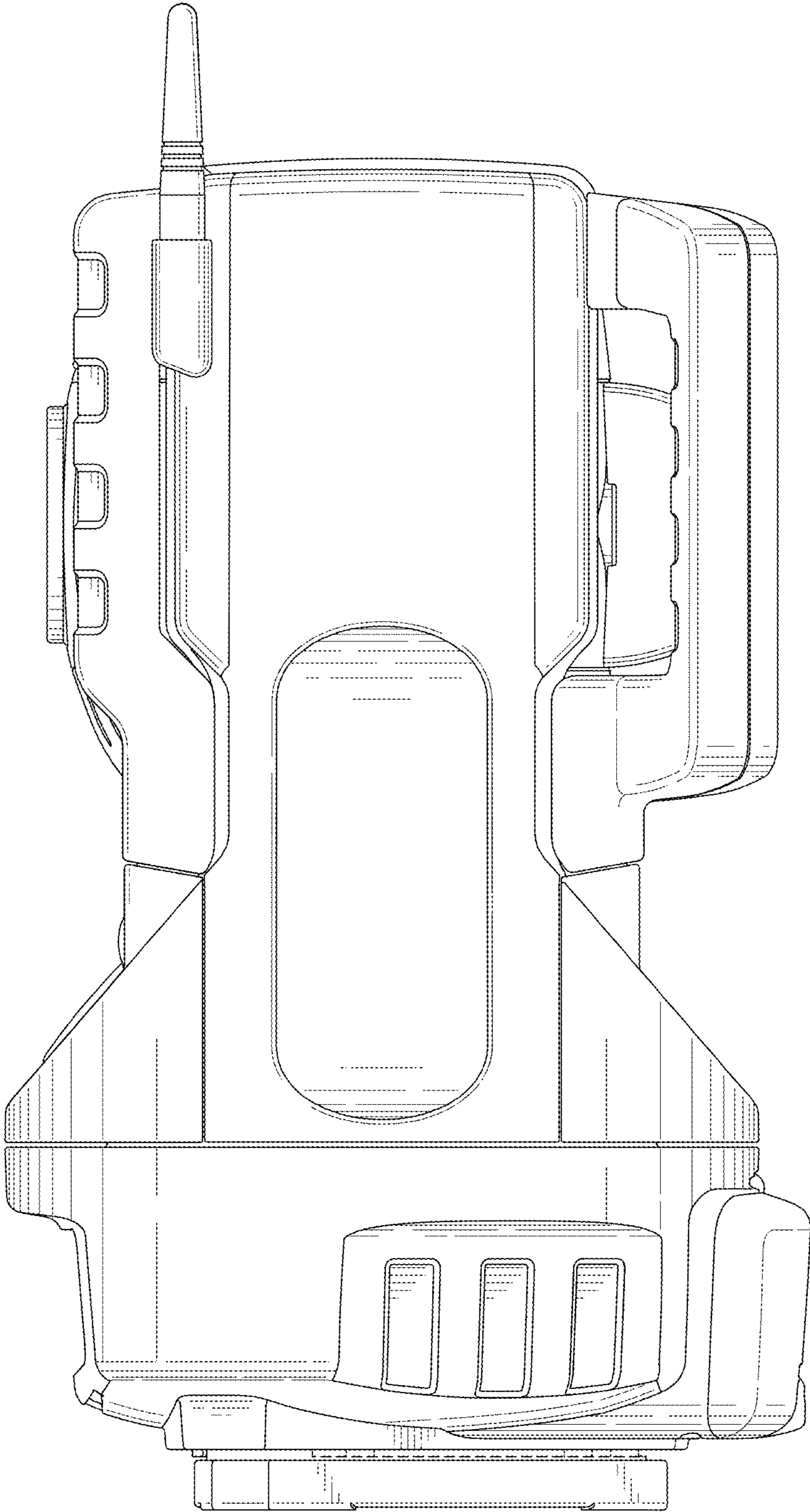


FIG. 4

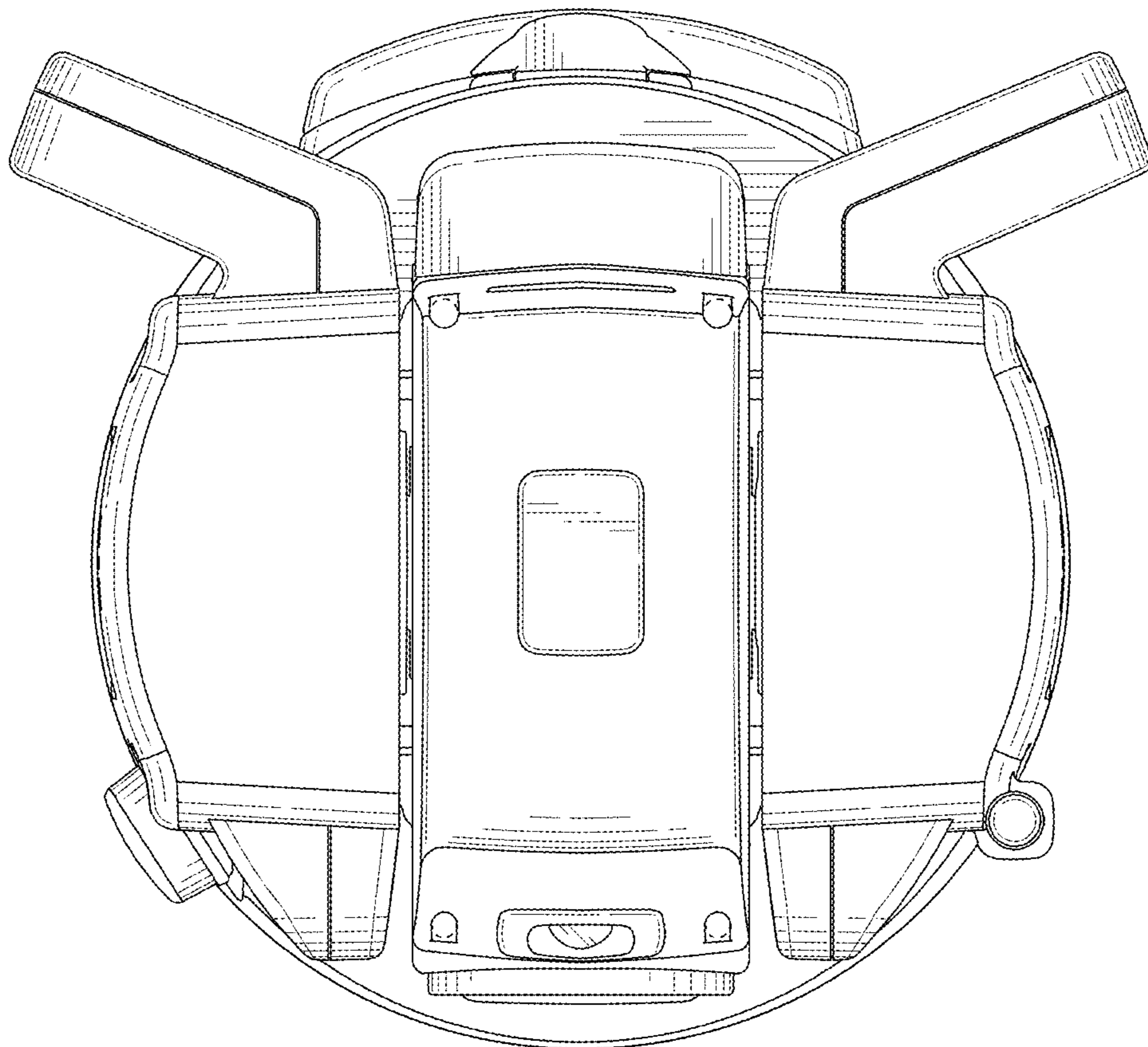


FIG. 5

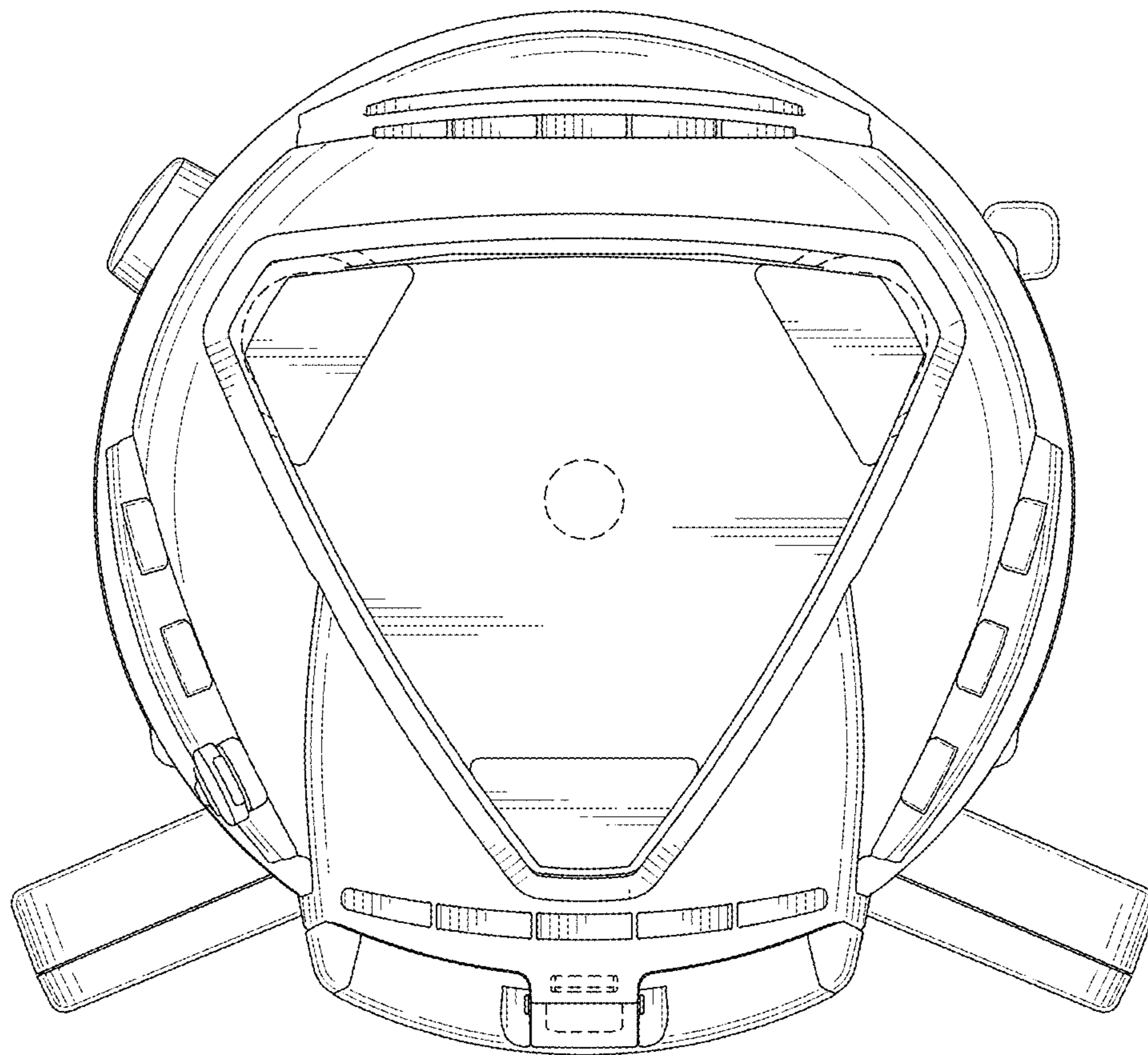


FIG. 6

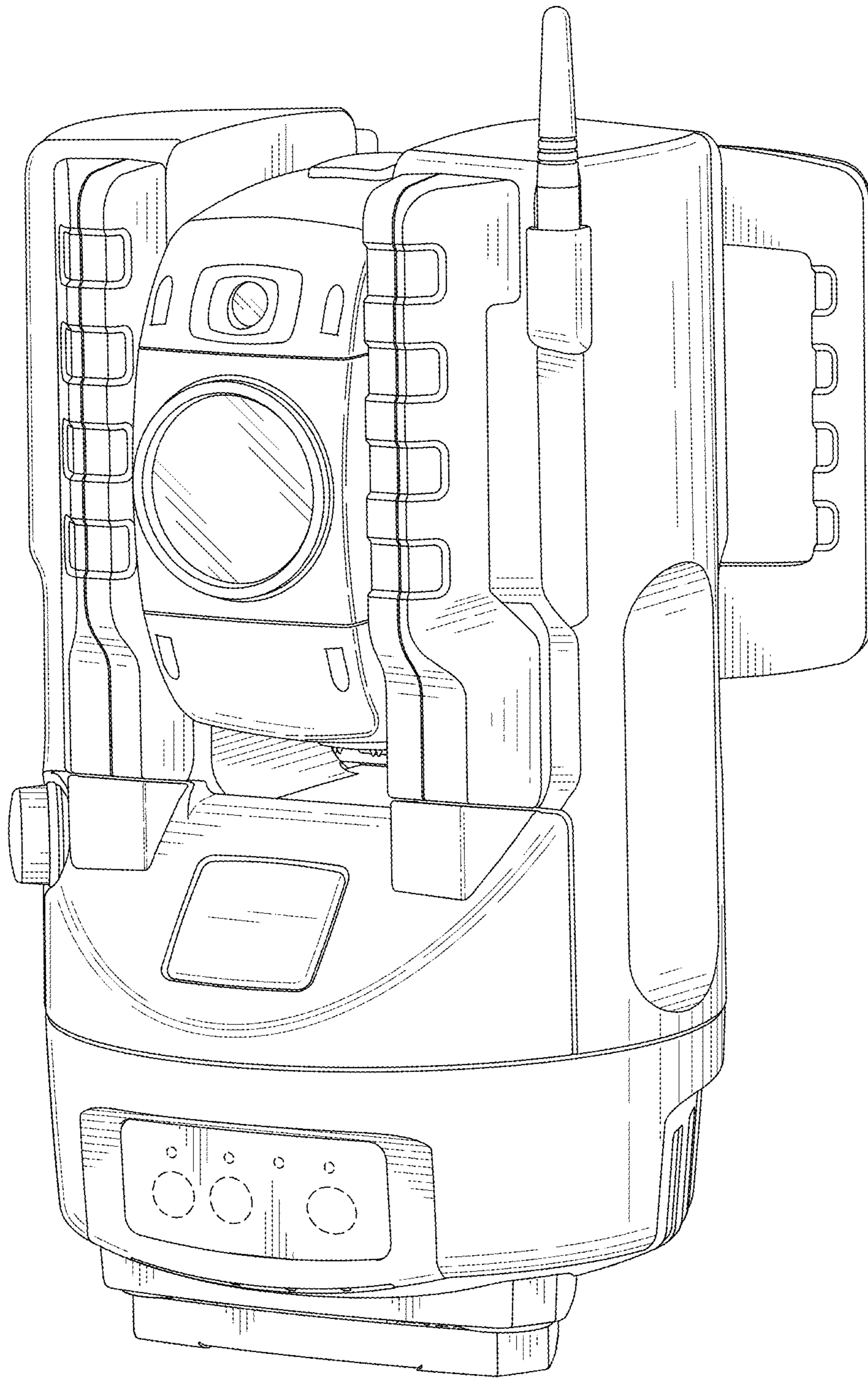


FIG. 7

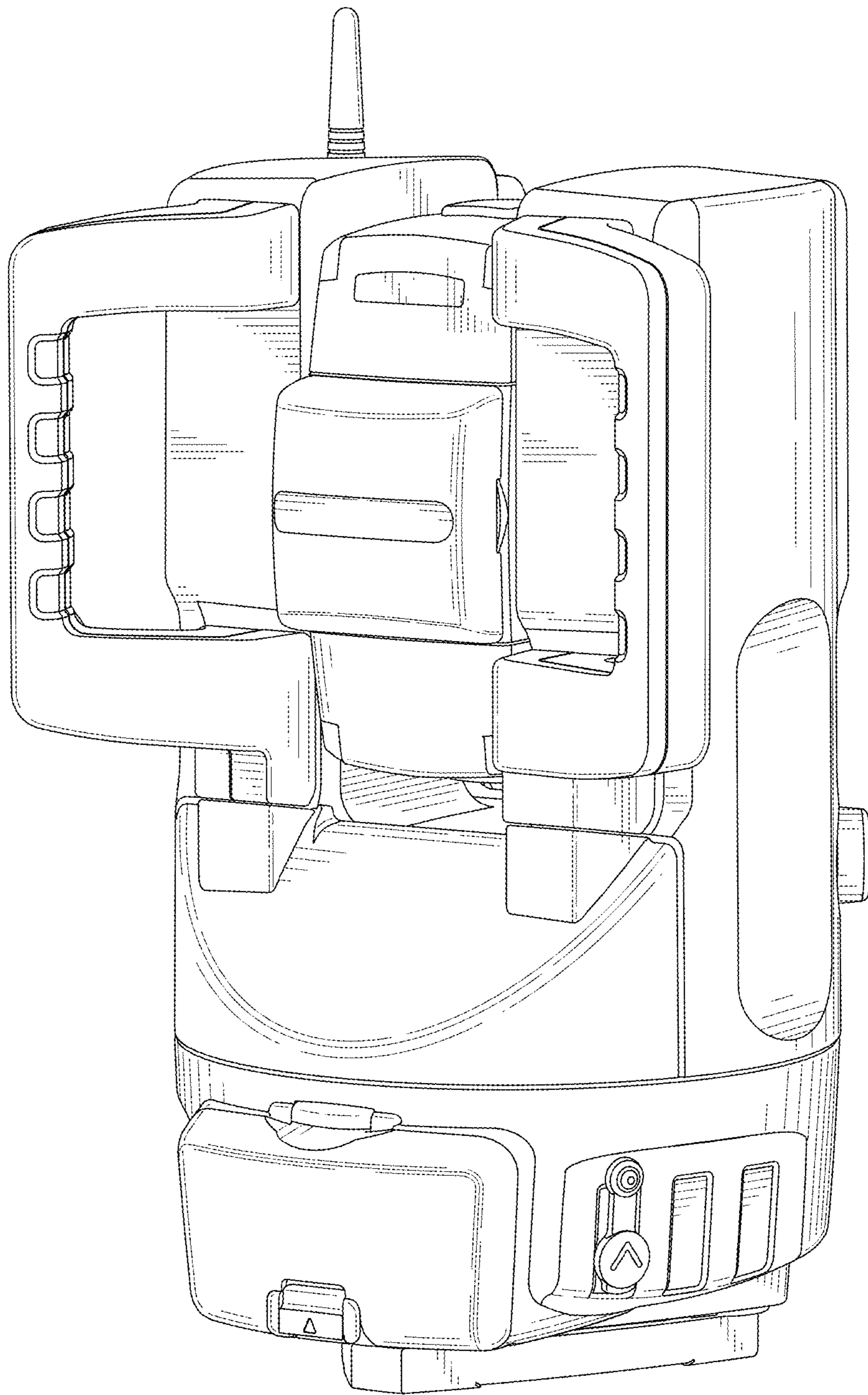


FIG. 8